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TRANSMITTAL OF FORMAL DRAWINGS	[1]	FIS920030031US1	
In Re Application Of: Xinhui Wang et al.			
Application No. Filing Date Examiner Customer No	Group Art Unit	Confirmation No.	
10/707,120 11/21/2003 Dung V. Nguyen 32074	3723	1119	
Invention: ENDPOINT DETECTION IN CHEMICAL-MECHANICAL POLISHING OF PATTERNED WAFERS HAVING A LOW PATTERN DENSITY			
Address to: Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450			
Transmitted herewith are:		1	
5 sheets of formal drawing(s) for this application.		1	
Each sheet of drawing indicates the identifying indicia suggested in 37 CFR Section 1.84(c).			
Jay H. Anderson	Novamber 2004	prrespondence is being	
2070 Route 52, Bldg. 300, Zip 482 Hopewell Junction, NY 12533-6531 deposited vsufficient position addressed to Alexandria, N	vith the United States	tes Postal Service with ss mail in an envelope Patents, P.O. Box 1450,	

Typed or Printed Name of Person Mailing Correspondence